

# STD110NH02L

# N-channel 24V - 0.0044Ω - 80A - DPAK STripFET™ III Power MOSFET

#### **General features**

Туре	V <sub>DSSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STD110NH02L	24V	<0.0048Ω	80A <sup>(1)</sup>

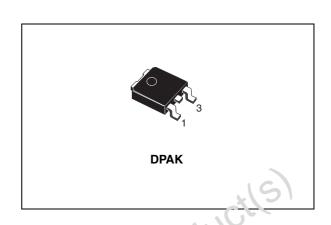
- 1. Value limited by wire bonding
- R<sub>DS(on)</sub> \* Qg industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device



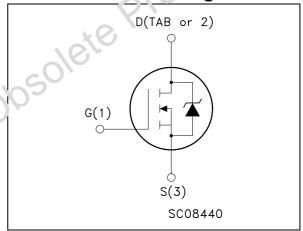
This device utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This is suitable fot the most demanding DC-DC converter application where high efficiency is to be achieved.

## **Applications**

iosolete Product(s)



#### Internal schematic diagram



#### **Order codes**

Part number	Part number Marking		Packaging
STD110NH02LT4	D110NH02L	DPAK	Tape & reel

Contents STD110NH02L

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STD110NH02L **Electrical ratings** 

#### **Electrical ratings** 1

Table 1. **Absolute maximum ratings** 

14510 11	1. Absolute maximum runings				
Symbol	Parameter	Value	Unit		
V <sub>spike</sub> (1)	Drain-source voltage rating	30	V		
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	24	V		
V <sub>DGR</sub>	Drain-gate voltage ( $R_{GS} = 20K\Omega$ )	24	V		
V <sub>GS</sub>	Drain-source voltage	± 20	V		
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>C</sub> = 25°C	80	Α		
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>C</sub> =100°C	80			
I <sub>DM</sub> <sup>(3)</sup>	Drain current (pulsed)	320			
P <sub>TOT</sub>	Total dissipation at $T_C = 25^{\circ}C$ 125		W		
	Derating factor	0.83	W/°C		
E <sub>AS</sub> (4)	Single pulse avalanche energy	900	mJ		
T <sub>stg</sub>	Storage temperature	-55 to 175	°C		
$T_J$	Max. operating junction temperature	-55 10 175			
<ol> <li>Garanted when external Rg = 4.7 Ω and t<sub>f</sub> &lt; t<sub>fmax</sub>.</li> <li>Value limited by wire bonding.</li> <li>Pulse width limited by safe operating area</li> <li>Starting T<sub>J</sub> = 25 °C, I<sub>D</sub> = 30A, V<sub>DD</sub> = 15V</li> </ol> Table 2. Thermal data					
Table 2.	Thermal data				

- 1. Garanted when external Rg = 4.7  $\Omega$  and  $t_{\text{f}}$  <  $t_{\text{fmax}}.$
- 2. Value limited by wire bonding.
- 3. Pulse width limited by safe operating area
- 4. Starting  $T_J = 25$  °C,  $I_D = 30A$ ,  $V_{DD} = 15V$

Table 2. Thermal data

	Symbol Parameter		Value	Unit
	R <sub>thJC</sub>	Thermal resistance junction-case Max	1.20	°C/W
	R <sub>thJA</sub>	Thermal resistance junction-ambient Max	100	°C/W
T <sub>I</sub> Maximum purpose		Maximum lead temperature for soldering purpose	275	°C
Obsolete				

STD110NH02L **Electrical characteristics** 

#### **Electrical characteristics** 2

(T<sub>CASE</sub>=25°C unless otherwise specified)

On<sup>(1)</sup> /off states Table 3.

Symbol	Parameter	Test conditions Min.			Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_D = 25 \text{mA}, V_{GS} = 0$	24			V
I <sub>DSS</sub>	Zero gate voltage drain current ( $V_{GS} = 0$ ) $V_{DS} = 20$ $V_{DS} = 20$ , $T_{C} = 125^{\circ}C$		1 10	μ <b>Α</b> μ <b>Α</b>		
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ±20V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1			V
R <sub>DS(on)</sub>	Static drain-source on resistance	$V_{GS} = 10V, I_D = 40A$ $V_{GS} = 5V, I_D = 20A$		0.0044 0.0050	0.0050 0.0095	$\Omega$
<ol> <li>Pulsed: Pulse duration = 300 μs, duty cycle 1.5%</li> <li>Table 4. Dynamic</li> </ol>						
Symbol	Parameter	Test conditions	Min	Tyn	May	Unit

<sup>1.</sup> Pulsed: Pulse duration =  $300 \mu s$ , duty cycle 1.5%

Table 4. **Dynamic** 

IUDIC T.	Dynamio					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	V <sub>DS</sub> = 10 V <sub>,</sub> I <sub>D</sub> = 40A		52		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 15V, f = 1 \text{ MHz}, V_{GS} = 0$		4450 1126 141		pF pF pF
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 10V, I_{D} = 80A$ $V_{GS} = 10V$		69 13 9	93	nC nC nC
Q <sub>oss</sub> <sup>(2)</sup>	Output charge	$V_{DS} = 16V, V_{GS} = 0V$		27		nC
Q <sub>gls</sub> <sup>(3)</sup>	Third-quadrant gate charge	V <sub>DS</sub> < 0V, V <sub>GS</sub> = 10V		64		nC
$R_{G}$	Gate input resistance	f = 1MHz gate DC Bias = 0 Test signal level = 20mV Open drain		16		Ω

<sup>1.</sup> Pulsed: pulse duration=300µs, duty cycle 1.5%

<sup>2.</sup>  $Q_{oss} = C_{oss}^* \Delta V_{in}$ ,  $C_{oss} = C_{gd} + C_{ds}$ . See *Section Appendix A* 

<sup>3.</sup> Gate charge for synchronous operation

Table 5. **Switching times** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$t_{\rm d(on)} \\ t_{\rm r} \\ t_{\rm d(off)} \\ t_{\rm f}$	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 10V$ , $I_D = 40A$ , $R_G = 4.7\Omega$ , $V_{GS} = 10V$ Figure 13 on page 8		14 224 69 40	54	ns ns ns ns

Table 6. Source drain diode

	Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
	I <sub>SD</sub>	Source-drain current				80	Α
	$I_{SDM}$	Source-drain current (pulsed)				320	Α
	$V_{SD}^{(1)}$	Forward on voltage	$I_{SD} = 40A, V_{GS} = 0$			1.3	٧
	t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD}$ = 80A, di/dt = 100A/ $\mu$ s, $V_{DD}$ = 15V, $T_{J}$ = 150°C Figure 15 on page 8	*0	47 58 2.5	il.	ns μC A
	1. Pulsed: p	oulse duration=300µs, duty cycle 1.5	5%				
1. Pulsed: pulse duration=300μs, duty cycle 1.5%							

Electrical characteristics STD110NH02L

# 2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

Figure 2. Thermal impedance

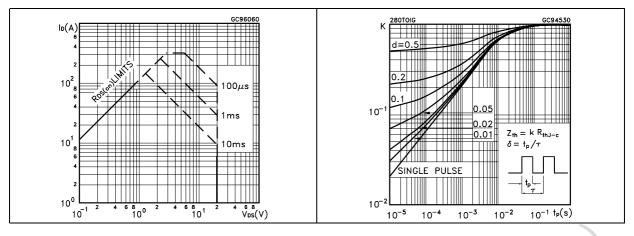


Figure 3. Output characterisics

Figure 4. Transfer characteristics

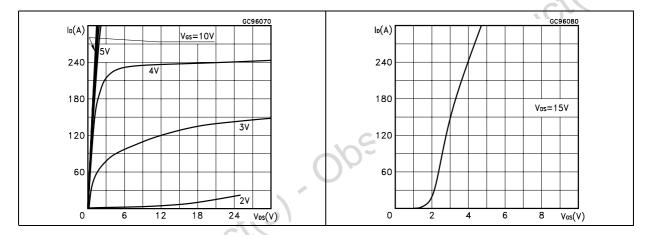


Figure 5. Transconductance

Figure 6. Static drain-source on resistance

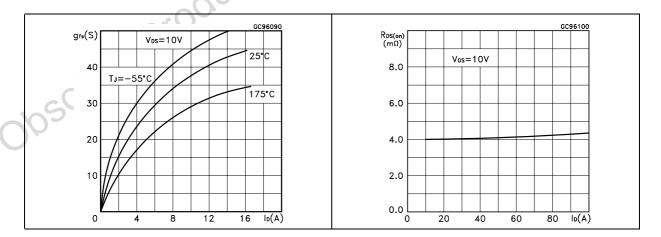


Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

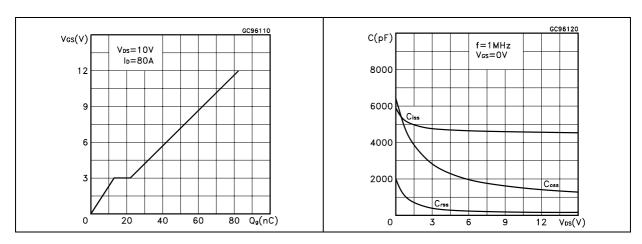


Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on resistance vs temperature

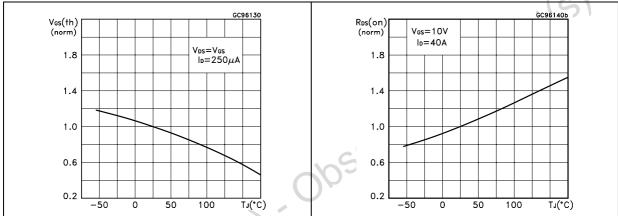
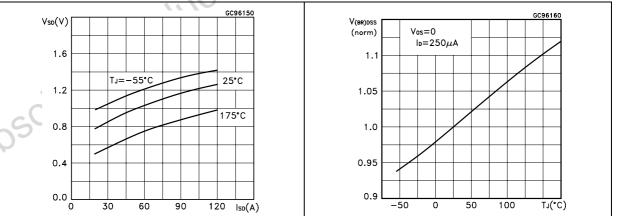


Figure 11. Source-drain diode forward characteristics

Figure 12. Normalized breakdown voltage vs temperature



Test circuit STD110NH02L

# 3 Test circuit

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

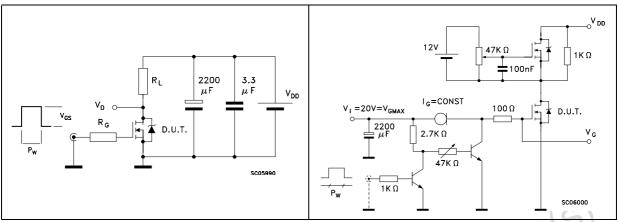


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped Inductive load test circuit

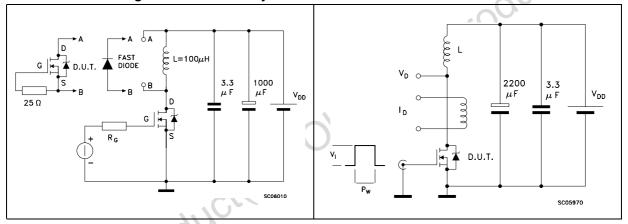
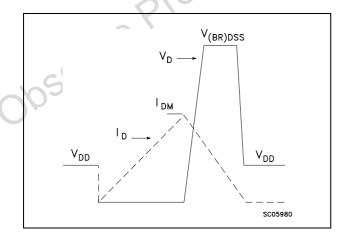


Figure 17. Unclamped inductive waveform



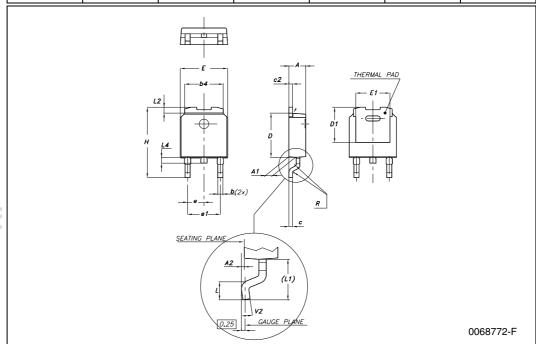
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

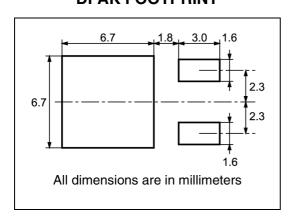
Obsolete Product(s). Obsolete Product(s)

#### **DPAK MECHANICAL DATA**

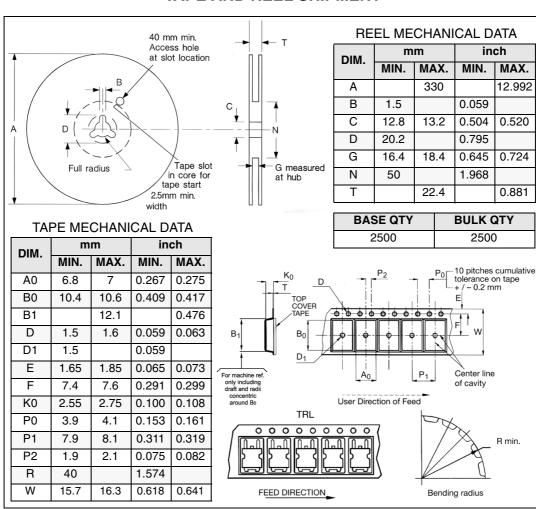
DIM		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
Е	6.4		6.6	0.252		0.260
E1		4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°



# 5 Packaging mechanical data DPAK FOOTPRINT



#### TAPE AND REEL SHIPMENT

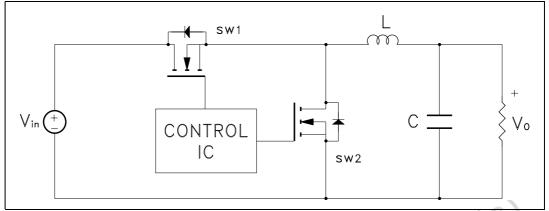






## Appendix A Buck converter - power losses estimation

Figure 18. Buck converter: power losses estimation



The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R<sub>DS(on)</sub> to reduce conduction losses
- Small Qgls to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R<sub>DS(on)</sub> to reduce the conduction losses.

Table 7. **Power losses calculation** 

		High side switching (SW1)	Low side switch (SW2)	
Pcond	luction	$R_{_{\mathrm{DS(on)SW1}}}*I_{\mathrm{L}}^{2}*\delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$	
Pswitching		$V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching	
Pdiode	Recovery (1)	Not applicable	$V_{in} * Q_{rr(SW2)} * f$	
Paloae	Conductio n	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$	
Pgate(Q <sub>G</sub> )		$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} * V_{gg} * f$	
P <sub>Qoss</sub>		$\frac{V_{in} *Q_{oss(SW1)} *f}{2}$	$\frac{V_{in} * Q_{oss(SW2)} * f}{2}$	
Dissipated by SW1 during turn-on				
able 8.	Paramite	rs meaning		
Parameter Meaning				

<sup>1.</sup> Dissipated by SW1 during turn-on

Paramiters meaning Table 8.

Parameter	Meaning
d	Duty-cycle
Q <sub>gsth</sub>	Post threshold gate charge
Q <sub>gls</sub>	Third quadrant gate charge
Pconduction	On state losses
Pswitching	On-off transition losses
Pdiode	Conduction and reverse recovery diode losses
Pgate	Gate drive losses
P <sub>Qoss</sub>	Output capacitance losses

Revision history STD110NH02L

# 6 Revision history

Table 9. Revision history

Date	Revision	Changes
09-Sep-2004	6	Complete version
08-Aug-2006	7	New template, updated SOA

Obsolete Product(s). Obsolete Product(s)

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